

# NCEP40T17A-VB Datasheet N-Channel 40 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ )	I <sub>D</sub> (A) <sup>a, c</sup>	Q <sub>g</sub> (Typ.)		
40	0.0010 at V <sub>GS</sub> = 10 V	280	240 nC		
	0.0012 at V <sub>GS</sub> = 4.5 V	250	240110		

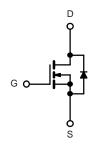
#### **FEATURES**

- Trench Power MOSFET
- 100 %  $R_g$  and UIS Tested



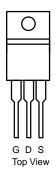
#### **APPLICATIONS**

- Synchronous Rectification
- Power Supplies



N-Channel MOSFET

## TO-220AB



<b>ABSOLUTE MAXIMUM RATINGS</b>	$T_A = 25$ °C, unles	ss otherwise no	oted	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V <sub>DS</sub>	40	V	
Gate-Source Voltage	V <sub>GS</sub>	± 25	]	
	T <sub>C</sub> = 25 °C		280 <sup>a, c</sup>	
Continuous Drain Current (T <sub>.1</sub> = 175 °C)	T <sub>C</sub> = 70 °C	, [	220 <sup>c</sup>	]
Continuous Diain Curient (1 j = 175 C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	229 <sup>b</sup>	A
	T <sub>A</sub> = 70 °C		223 <sup>b</sup>	1 ^
Pulsed Drain Current	I <sub>DM</sub>	750	1	
Avalanche Current Pulse	L = 0.1 mH	I <sub>AS</sub>	80	1
Single Pulse Avalanche Energy	L=0.1 IIIA	E <sub>AS</sub>	320	V
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C	L	110 <sup>a, c</sup>	A
Continuous Source-Diam Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	2.6 <sup>b</sup>	7
	T <sub>C</sub> = 25 °C		312 <sup>a</sup>	
Marianum Barras Biosination	T <sub>C</sub> = 70 °C	В	200	100
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.13 <sup>b</sup>	W
	T <sub>A</sub> = 70 °C		2.0 <sup>b</sup>	1
Operating Junction and Storage Temperature Ran	T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient <sup>b</sup>	Steady State	R <sub>thJA</sub>	32	40	°C/W		
Maximum Junction-to-Case	Steady State	$R_{thJC}$	0.33	0.4	C/VV		

#### Notes:

- a. Based on  $T_C = 25$  °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. Calculated based on maximum junction temperature. Package limitation current is 110  $\,\mathrm{A.}$



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	45			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L = 250 µA		41		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	ι <sub>D</sub> = 230 μΑ		- 8		miv/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.2		2.5	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zoro Coto Voltogo Droin Current	1	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V	$V_{GS} = 0 \text{ V, } I_D = 250 \text{ μA}$ $I_D = 250 \text{ μA}$ $I_D = 250 \text{ μA}$ $V_{DS} = V_{GS}, I_D = 250 \text{ μA}$ $V_{DS} = 0 \text{ V, } V_{GS} = \pm 20 \text{ V}$ $V_{DS} = 40 \text{ V, } V_{GS} = 0 \text{ V}$ $S = 40 \text{ V, } V_{GS} = 0 \text{ V, } I_D = 55 \text{ °C}$ $V_{DS} \ge 5 \text{ V, } V_{GS} = 10 \text{ V}$ $V_{GS} = 10 \text{ V, } I_D = 30 \text{ A}$ $V_{DS} = 15 \text{ V, } I_D = 30 \text{ A}$ $V_{DS} = 15 \text{ V, } I_D = 30 \text{ A}$ $V_{DS} = 15 \text{ V, } I_D = 30 \text{ A}$ $S = 20 \text{ V, } V_{GS} = 0 \text{ V, } f = 1 \text{ MHz}$ $S = 20 \text{ V, } V_{GS} = 10 \text{ V, } I_D = 20 \text{ A}$ $S = 20 \text{ V, } I_D = 20 \text{ V, } I_D = 20 \text{ A}$ $S = 20 \text{ V, } I_D = 20 \text{ V, } I_D = 20 \text{ A}$ $S = 20 \text{ V, } I_D = 20 \text{ V, } I_D = 20 \text{ A}$ $S = 20 \text{ V, } I_D = 20 \text{ V, } I_D = 20 \text{ A}$ $S = 20 \text{ V, } I_D = 20 \text{ V, } I_D = 20 \text{ A}$ $S = 20 \text{ V, } I_D = 20 \text{ V, } I_D = 20 \text{ A}$ $S = 20 \text{ V, } I_D = 20 \text{ V, } I_D = 20 \text{ A}$ $S = 20 \text{ V, } I_D = 20$	1		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	μA
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	120			Α
5 1 6 6 7 3	В	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		0.0010		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 4.5 \text{ V}, I_D = 20 \text{ A}$		0.0012		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 15 \text{ V}, I_{D} = 30 \text{ A}$		180		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>			18800		pF
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1550		
Reverse Transfer Capacitance	C <sub>rss</sub>			850		
Total Gate Charge	Qg			240	360	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 20 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 20 \text{ A}$		40		nC
Gate-Drain Charge	Q <sub>gd</sub>	D3 - 7 G3 - 7 D		22		1
Gate Resistance	$R_{g}$	f = 1 MHz		0.85	1.3	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			20	30	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, $R_L$ = 1.0 $\Omega$		11	17	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 20$ A, $V_{GEN}$ = 10 V, $R_g$ = 1 $\Omega$		77	115	
Fall Time	t <sub>f</sub>			10	15	
Turn-On Delay Time	t <sub>d(on)</sub>			102	155	ns
Rise Time	t <sub>r</sub>	$V_{DD}$ = 20 V, $R_L$ = 1.0 $\Omega$		62	95	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 20 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		180	270	
Fall Time	t <sub>f</sub>			60	90	1
<b>Drain-Source Body Diode Characteristic</b>	s					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			110	A
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				200	_ ^
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = 20 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			50	75	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	1 20 A di/dt 100 A/v- T 05 00		70	105	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 20 \text{ A}$ , $I_J = 25 ^{\circ}\text{C}$		30		
Reverse Recovery Rise Time	t <sub>b</sub>			20		ns

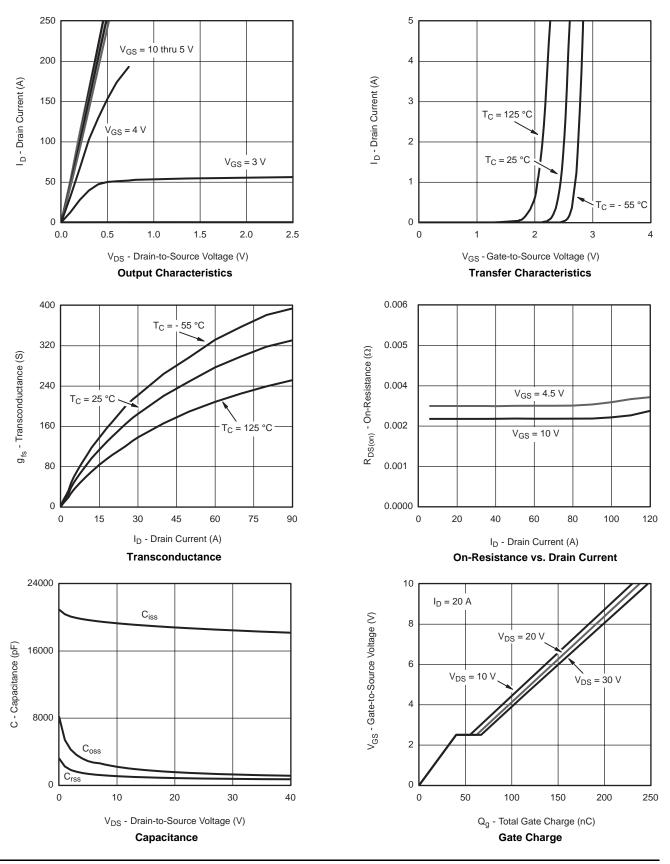
#### Notes:

- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

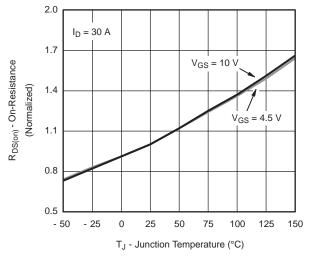


## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

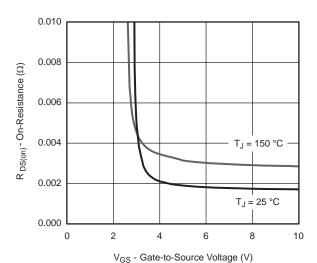




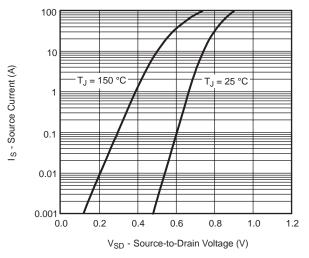
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#### On-Resistance vs. Junction Temperature



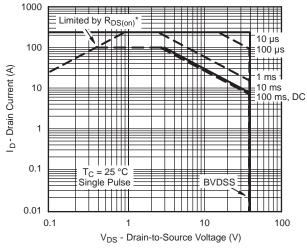
On-Resistance vs. Gate-to-Source Voltage



#### Forward Diode Voltage vs. Temperature



Threshold Voltage

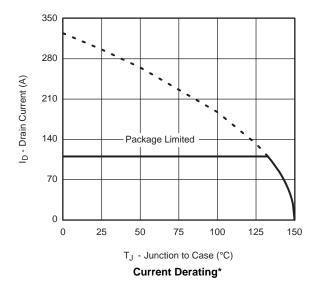


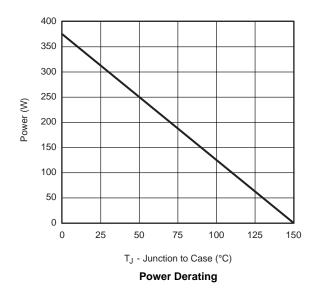
\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

Safe Operating Area, Junction-to-Ambient

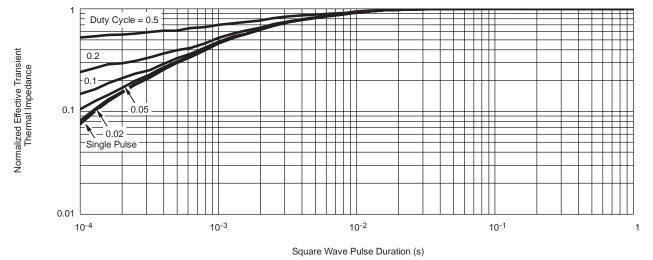


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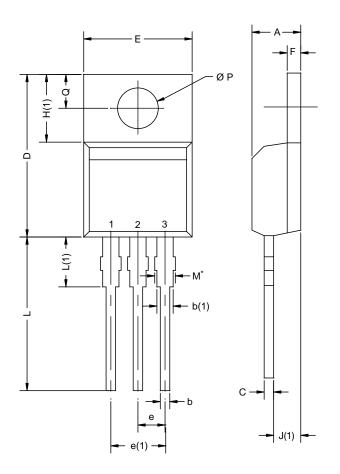
<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)}$  = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



Normalized Thermal Transient Impedance, Junction-to-Case



# **TO-220AB**



	MILLIM	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471					

#### Notes

 $<sup>^{\</sup>star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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